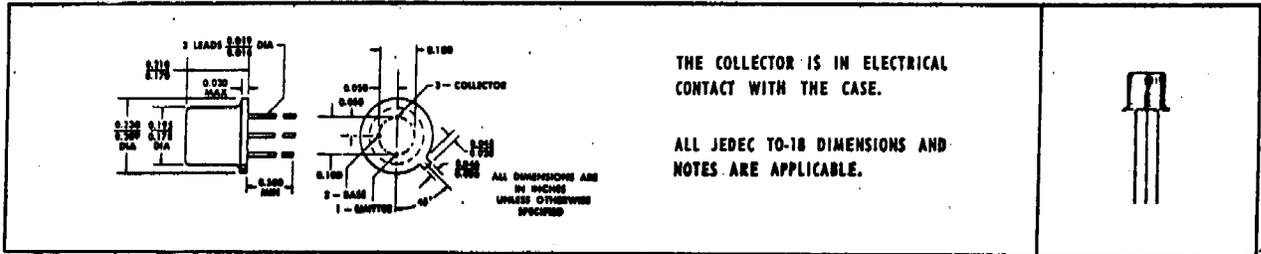


**TYPES 2N3033, 2N3034, 2N3035**

**N-P-N EPITAXIAL MESA SILICON TRANSISTORS**

**DESIGNED FOR EXTREMELY-HIGH-SPEED, HIGH-CURRENT  
 AVALANCHE-MODE SWITCHING APPLICATIONS**

- Strobe-Pulse Generators
- Square-Wave Pulse Generators
- Memory-Core Drivers

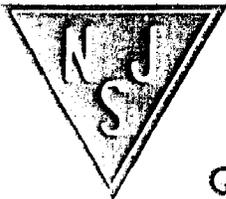


**absolute maximum ratings at 25°C free-air temperature (unless otherwise noted)**

Emitter-Base Voltage	4 v
Collector Current, Continuous	200 ma
Collector Current, Peak (See Note 1)	10 a
Total Device Dissipation at (or below) 25°C Free-Air Temperature (See Note 2)	300 mw
Total Device Dissipation at (or below) 25°C Case Temperature (See Note 3)	1.0 w
Storage Temperature Range	-65°C to +200°C

**electrical characteristics at 25°C free-air temperature (unless otherwise noted)**

PARAMETER	TEST CONDITIONS	2N3033		2N3034		2N3035		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	
$BV_{CBO}$ Collector-Base Breakdown Voltage	$I_C = 1 \text{ ma}$ , $I_E = 0$	100	160	70	120	50	90	v
$BV_{CEB}$ Collector-Emitter Breakdown Voltage	$I_C = 1 \text{ ma}$ , $R_{BE} = 100 \Omega$	100	150	70	110	50	80	v
$BV_{EBO}$ Emitter-Base Breakdown Voltage	$I_E = 10 \mu\text{a}$ , $I_C = 0$	4		4		4		v
$I_{CBO}$ Collector Cutoff Current	$V_{CB} - \text{See Note 4}$ , $I_E = 0$		5		5		5	$\mu\text{a}$
$I_{CBR}$ Collector Cutoff Current	$V_{CE} - \text{See Note 5}$ , $R_{BE} = 100 \Omega$		5		5		5	$\mu\text{a}$
	$V_{CE} = 90 \text{ v}$ , $R_{BE} = 100 \Omega$ , $T_A = 125^\circ\text{C}$		50					$\mu\text{a}$
	$V_{CE} = 60 \text{ v}$ , $R_{BE} = 100 \Omega$ , $T_A = 125^\circ\text{C}$				50			$\mu\text{a}$
$I_{EB}$ Emitter Cutoff Current	$V_{EB} = 3 \text{ v}$ , $I_C = 0$		1		1		1	$\mu\text{a}$
$I_{CES(H)}$ Collector Hold-Off Current	$V_{BE} = 0$ , (See Note 6)	2.0		2.0		2.0		ma
$I_{CER(H)}$ Collector Hold-Off Current	$R_{BE} = 100 \Omega$ , (See Note 6)	1.5		1.5		1.5		ma
$V_{BE}$ Base-Emitter Voltage	$I_E = 20 \text{ ma}$ , $I_C = 100 \text{ ma}$		1.5		1.5		1.5	v
$V_{CE(sat)}$ Collector-Emitter Saturation Voltage	$I_E = 20 \text{ ma}$ , $I_C = 100 \text{ ma}$		1.0		1.0		1.0	v
$C_{ob}$ Common-Base Open-Circuit Output Capacitance	$V_{CB} = 10 \text{ v}$ , $I_E = 0$ , $f = 140 \text{ kc}$		6		6		6	pf
$C_{ib}$ Common-Base Open-Circuit Input Capacitance	$V_{EB} = 1 \text{ v}$ , $I_C = 0$ , $f = 140 \text{ kc}$		10		10		10	pf



NJ Semi-Conductors reserves the right to change test conditions, parameter limits and package dimensions without notice. Information furnished by NJ Semi-Conductors is believed to be both accurate and reliable at the time of going to press. However, NJ Semi-Conductors assumes no responsibility for any errors or omissions discovered in its use. NJ Semi-Conductors encourages customers to verify that datasheets are current before placing orders.

**Quality Semi-Conductors**

- NOTES: 1. This value applies for  $PW \leq 25$  nsec, Duty Cycle  $\leq 0.05\%$ .
2. Derate linearly to 175°C free-air temperature at the rate of 2.0 mw/C°.
3. Derate linearly to 175°C case temperature at the rate of 6.67 mw/C°.
4. This parameter is measured at a collector-base voltage 15 v below the actual  $BV_{CBO}$  at  $I_C = 1$  ma,  $I_B = 0$ .
5. This parameter is measured at a collector-emitter voltage 15 v below the actual  $BV_{CEB}$  at  $I_C = 1$  ma,  $R_{BE} = 100 \Omega$ .
6. Collector Hold-Off Current is defined as that value of collector cutoff current above which the reverse voltage-current characteristic exhibits negative resistance. These parameters are measured by a sweep method using a transistor curve tracer.

**switching characteristics at 25°C free-air temperature**

PARAMETER	TEST CONDITIONS	2N3033		2N3034		2N3035		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	
$t_d$ Delay Time	See Figure 1	3		3		3		nsec
$t_r$ Rise Time		2		2		2		nsec
$V_o$ Output Pulse Amplitude		45		30		20		v